

Diagonal 8mm (Type 1/2) CCD Image Sensor for EIA Black-and-White Video Cameras

Description

The ICX248AL is an interline CCD solid-state image sensor suitable for EIA black-and-white video cameras with a diagonal 8mm (Type 1/2) system. Sensitivity, smear, D-range, S/N and other characteristics from visible light area to near infrared light area, have been greatly improved compared with the ICX038DLA through the adoption of EXview HAD CCD™ technology.

This chip features a field period readout system and an electronic shutter with variable charge-storage time.

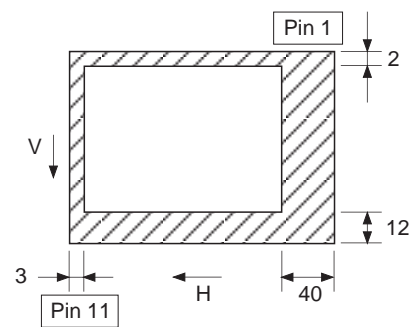
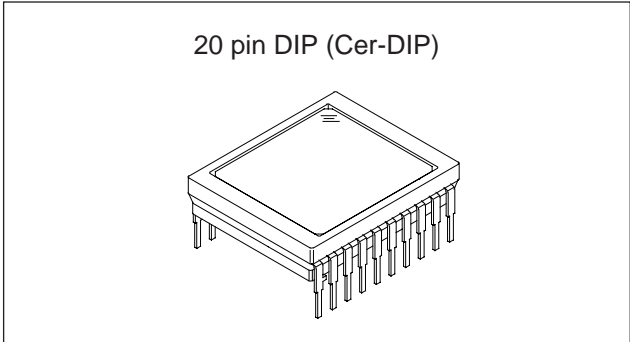
This chip is compatible with and can replace the ICX038DLA.

Features

- Sensitivity in the near infrared light area (+12dB compared with the ICX038DLA, $\lambda = 945\text{nm}$)
- High sensitivity (+9dB compared with the ICX038DLA, without IR cut filter)
- Low smear (-15dB compared with the ICX038DLA)
- High D range (+2dB compared with the ICX038DLA)
- High S/N
- High resolution and low dark current
- Excellent antiblooming characteristics
- Continuous variable-speed shutter
- Substrate bias: Adjustment free (external adjustment also possible with 6 to 14V)
- Reset gate pulse: 5Vp-p adjustment free (drive also possible with 0 to 9V)
- Horizontal register: 5V drive

Device Structure

- Interline CCD image sensor
- Image size: Diagonal 8mm (Type 1/2)
- Number of effective pixels: 768 (H) × 494 (V) approx. 380K pixels
- Total number of pixels: 811 (H) × 508 (V) approx. 410K pixels
- Chip size: 7.95mm (H) × 6.45mm (V)
- Unit cell size: 8.4 μm (H) × 9.8 μm (V)
- Optical black:
 - Horizontal (H) direction: Front 3 pixels, rear 40 pixels
 - Vertical (V) direction: Front 12 pixels, rear 2 pixels
- Number of dummy bits:
 - Horizontal 22
 - Vertical 1 (even fields only)
- Substrate material: Silicon



Optical black position (Top View)

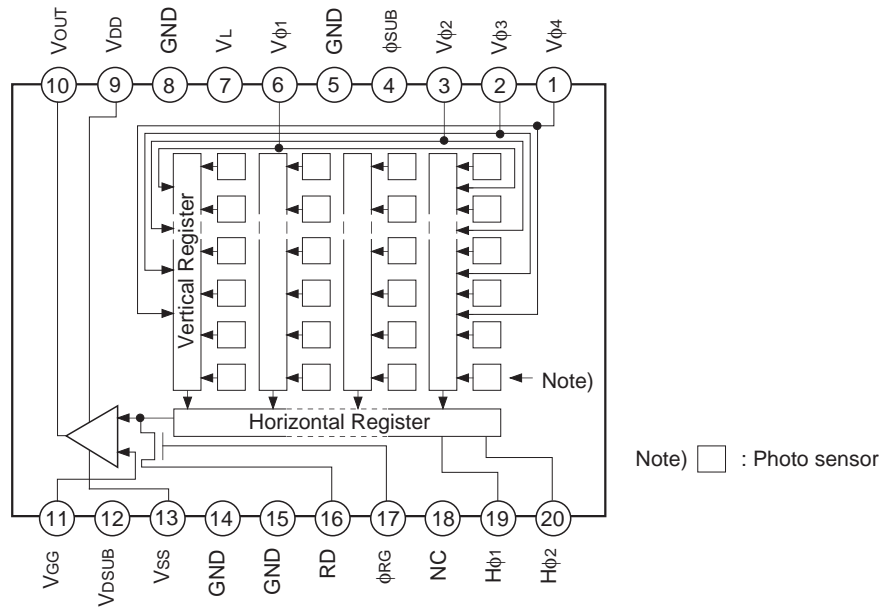
EXview HAD CCD™

* EXview HAD CCD is a trademark of Sony Corporation EXview HAD CCD is a CCD that drastically improves light efficiency by including near infrared light region as a basic structure of HAD (Hole-Accumulation Diode) sensor.

Sony reserves the right to change products and specifications without prior notice. This information does not convey any license by any implication or otherwise under any patents or other right. Application circuits shown, if any, are typical examples illustrating the operation of the devices. Sony cannot assume responsibility for any problems arising out of the use of these circuits.

Block Diagram and Pin Configuration

(Top View)



Pin Description

| Pin No. | Symbol | Description | Pin No. | Symbol | Description |
|---------|--------|----------------------------------|---------|--------|---------------------------------------|
| 1 | Vφ4 | Vertical register transfer clock | 11 | VGG | Output circuit gate bias |
| 2 | Vφ3 | Vertical register transfer clock | 12 | VDSUB | Substrate bias circuit supply voltage |
| 3 | Vφ2 | Vertical register transfer clock | 13 | VSS | Output circuit source |
| 4 | φSUB | Substrate clock | 14 | GND | GND |
| 5 | GND | GND | 15 | GND | GND |
| 6 | Vφ1 | Vertical register transfer clock | 16 | RD | Reset drain bias |
| 7 | VL | Protective transistor bias | 17 | φRG | Reset gate clock |
| 8 | GND | GND | 18 | NC | |
| 9 | VDD | Output circuit supply voltage | 19 | Hφ1 | Horizontal register transfer clock |
| 10 | VOUT | Signal output | 20 | Hφ2 | Horizontal register transfer clock |

Absolute Maximum Ratings

| Item | | Ratings | Unit | Remarks |
|--|--|-------------|------|---------|
| Substrate clock $\phi_{\text{SUB}} - \text{GND}$ | | -0.3 to +50 | V | |
| Supply voltage | $V_{\text{DD}}, V_{\text{RD}}, V_{\text{DSUB}}, V_{\text{OUT}}, V_{\text{SS}} - \text{GND}$ | -0.3 to +18 | V | |
| | $V_{\text{DD}}, V_{\text{RD}}, V_{\text{DSUB}}, V_{\text{OUT}}, V_{\text{SS}} - \phi_{\text{SUB}}$ | -55 to +10 | V | |
| Clock input voltage | $V_{\phi 1}, V_{\phi 2}, V_{\phi 3}, V_{\phi 4} - \text{GND}$ | -15 to +20 | V | |
| | $V_{\phi 1}, V_{\phi 2}, V_{\phi 3}, V_{\phi 4} - \phi_{\text{SUB}}$ | to +10 | V | |
| Voltage difference between vertical clock input pins | | to +15 | V | *1 |
| Voltage difference between horizontal clock input pins | | to +17 | V | |
| $H_{\phi 1}, H_{\phi 2} - V_{\phi 4}$ | | -17 to +17 | V | |
| $\phi_{\text{RG}}, V_{\text{GG}} - \text{GND}$ | | -10 to +15 | V | |
| $\phi_{\text{RG}}, V_{\text{GG}} - \phi_{\text{SUB}}$ | | -55 to +10 | V | |
| $V_{\text{L}} - \phi_{\text{SUB}}$ | | -65 to +0.3 | V | |
| Pins other than GND and $\phi_{\text{SUB}} - V_{\text{L}}$ | | -0.3 to +30 | V | |
| Storage temperature | | -30 to +80 | °C | |
| Operating temperature | | -10 to +60 | °C | |

*1 +27V (Max.) when clock width < 10 μ s, clock duty factor < 0.1%.

Bias Conditions 1 [when used in substrate bias internal generation mode]

| Item | Symbol | Min. | Typ. | Max. | Unit | Remarks | |
|---------------------------------------|-------------------|-----------------------------|------|-------|------|-----------------------------------|--|
| Output circuit supply voltage | V _{DD} | 14.55 | 15.0 | 15.45 | V | | |
| Reset drain voltage | V _{RD} | 14.55 | 15.0 | 15.45 | V | V _{RD} = V _{DD} | |
| Output circuit gate voltage | V _{GG} | 1.75 | 2.0 | 2.25 | V | | |
| Output circuit source | V _{SS} | Grounded with 390Ω resistor | | | | | |
| Protective transistor bias | V _L | *1 | | | | | |
| Substrate bias circuit supply voltage | V _{DSUB} | 14.55 | 15.0 | 15.45 | V | | |
| Substrate clock | φ _{SUB} | *2 | | | | | |

*1 V_L setting is the V_{VL} voltage of the vertical transfer clock waveform, or the same power supply as the V_L power supply for the V driver should be used. (When CXD1267AN is used.)

*2 Do not apply a DC bias to the substrate clock pin, because a DC bias is generated within the CCD.

Bias Conditions 2 [when used in substrate bias external adjustment mode]

| Item | Symbol | Min. | Typ. | Max. | Unit | Remarks | |
|--|-------------------|-----------------------------|------|-------|------|-----------------------------------|--|
| Output circuit supply voltage | V _{DD} | 14.55 | 15.0 | 15.45 | V | | |
| Reset drain voltage | V _{RD} | 14.55 | 15.0 | 15.45 | V | V _{RD} = V _{DD} | |
| Output circuit gate voltage | V _{GG} | 1.75 | 2.0 | 2.25 | V | | |
| Output circuit source | V _{SS} | Grounded with 390Ω resistor | | | | | |
| Protective transistor bias | V _L | *3 | | | | | |
| Substrate bias circuit supply voltage | V _{DSUB} | *4 | | | | | |
| Substrate voltage adjustment range | V _{SUB} | 6.0 | | 14.0 | V | *5 | |
| Substrate voltage adjustment precision | ΔV _{SUB} | -3 | | +3 | % | *5 | |

*3 V_L setting is the V_{VL} voltage of the vertical transfer clock waveform, or the same power supply as the V_L power supply for the V driver should be used. (When CXD1267AN is used.)

*4 Connect to GND or leave open.

*5 The setting value of the substrate voltage (V_{SUB}) is indicated on the back of the image sensor by a special code. When adjusting the substrate voltage externally, adjust the substrate voltage to the indicated voltage. The adjustment precision is ±3%. However, this setting value has not significance when used in substrate bias internal generation mode.

V_{SUB} code — one character indication

Code and optimal setting correspond to each other as follows.

| V _{SUB} code | E | f | G | h | J | K | L | m | N | P | Q | R | S | T | U | V | W |
|-----------------------|-----|-----|-----|-----|-----|-----|-----|-----|------|------|------|------|------|------|------|------|------|
| Optimal setting | 6.0 | 6.5 | 7.0 | 7.5 | 8.0 | 8.5 | 9.0 | 9.5 | 10.0 | 10.5 | 11.0 | 11.5 | 12.0 | 12.5 | 13.0 | 13.5 | 14.0 |

<Example> "L" → V_{SUB} = 9.0V

DC Characteristics

| Item | Symbol | Min. | Typ. | Max. | Unit | Remarks |
|-------------------------------|-----------------|------|------|------|------|---------|
| Output circuit supply current | I _{DD} | | 5.0 | 10.0 | mA | |

Clock Voltage Conditions

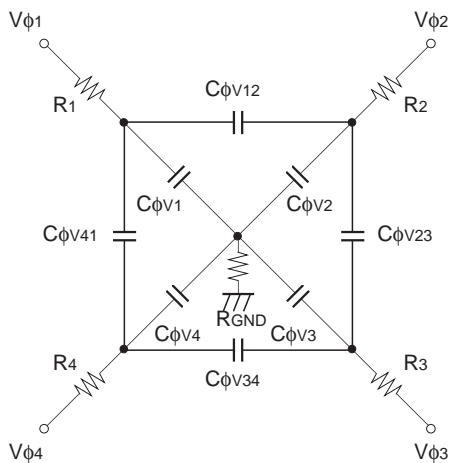
| Item | Symbol | Min. | Typ. | Max. | Unit | Waveform diagram | Remarks |
|-----------------------------------|--------------------------------------|-------|------|-------|------|------------------|--|
| Readout clock voltage | V_{VT} | 14.55 | 15.0 | 15.45 | V | 1 | |
| Vertical transfer clock voltage | V_{VH1}, V_{VH2} | -0.05 | 0 | 0.05 | V | 2 | $V_{VH} = (V_{VH1} + V_{VH2})/2$ |
| | V_{VH3}, V_{VH4} | -0.2 | 0 | 0.05 | V | 2 | |
| | $V_{VL1}, V_{VL2}, V_{VL3}, V_{VL4}$ | -9.6 | -9.0 | -8.5 | V | 2 | $V_{VL} = (V_{VL3} + V_{VL4})/2$ |
| | $V_{\phi V}$ | 8.3 | 9.0 | 9.65 | Vp-p | 2 | $V_{\phi V} = V_{VHn} - V_{VLn} (n = 1 \text{ to } 4)$ |
| | $ V_{VH1} - V_{VH2} $ | | | 0.1 | V | 2 | |
| | $V_{VH3} - V_{VH}$ | -0.25 | | 0.1 | V | 2 | |
| | $V_{VH4} - V_{VH}$ | -0.25 | | 0.1 | V | 2 | |
| | V_{VHH} | | | 0.5 | V | 2 | High-level coupling |
| | V_{VHL} | | | 0.5 | V | 2 | High-level coupling |
| | V_{VLH} | | | 0.5 | V | 2 | Low-level coupling |
| | V_{VLL} | | | 0.5 | V | 2 | Low-level coupling |
| Horizontal transfer clock voltage | $V_{\phi H}$ | 4.75 | 5.0 | 5.25 | Vp-p | 3 | |
| | V_{HL} | -0.05 | 0 | 0.05 | V | 3 | |
| Reset gate clock voltage*1 | V_{RGL} | *1 | | | V | 4 | |
| | $V_{\phi RG}$ | 4.5 | 5.0 | 5.5 | Vp-p | 4 | |
| | $V_{RGLH} - V_{RGLL}$ | | | 0.8 | V | 4 | Low-level coupling |
| Substrate clock voltage | $V_{\phi SUB}$ | 23.0 | 24.0 | 25.0 | Vp-p | 5 | |

*1 Input the reset gate clock without applying a DC bias. In addition, the reset gate clock can also be driven with the following specifications.

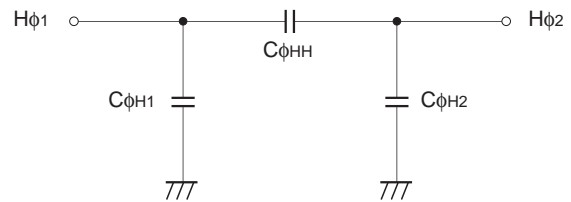
| Item | Symbol | Min. | Typ. | Max. | Unit | Waveform diagram | Remarks |
|--------------------------|---------------|------|------|------|------|------------------|---------|
| Reset gate clock voltage | V_{RGL} | -0.2 | 0 | 0.2 | V | 4 | |
| | $V_{\phi RG}$ | 8.5 | 9.0 | 9.5 | Vp-p | 4 | |

Clock Equivalent Circuit Constant

| Item | Symbol | Min. | Typ. | Max. | Unit | Remarks |
|---|----------------------------|------|------|------|----------|---------|
| Capacitance between vertical transfer clock and GND | $C\phi_{V1}, C\phi_{V3}$ | | 1800 | | pF | |
| | $C\phi_{V2}, C\phi_{V4}$ | | 2200 | | pF | |
| Capacitance between vertical transfer clocks | $C\phi_{V12}, C\phi_{V34}$ | | 450 | | pF | |
| | $C\phi_{V23}, C\phi_{V41}$ | | 270 | | pF | |
| Capacitance between horizontal transfer clock and GND | $C\phi_{H1}$ | | 64 | | pF | |
| | $C\phi_{H2}$ | | 62 | | pF | |
| Capacitance between horizontal transfer clocks | $C\phi_{HH}$ | | 47 | | pF | |
| Capacitance between reset gate clock and GND | $C\phi_{RG}$ | | 8 | | pF | |
| Capacitance between substrate clock and GND | $C\phi_{SUB}$ | | 400 | | pF | |
| Vertical transfer clock series resistor | R_1, R_2, R_3, R_4 | | 68 | | Ω | |
| Vertical transfer clock ground resistor | R_{GND} | | 15 | | Ω | |



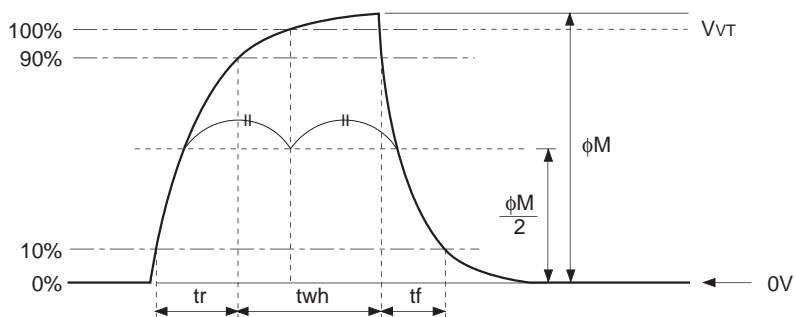
Vertical transfer clock equivalent circuit



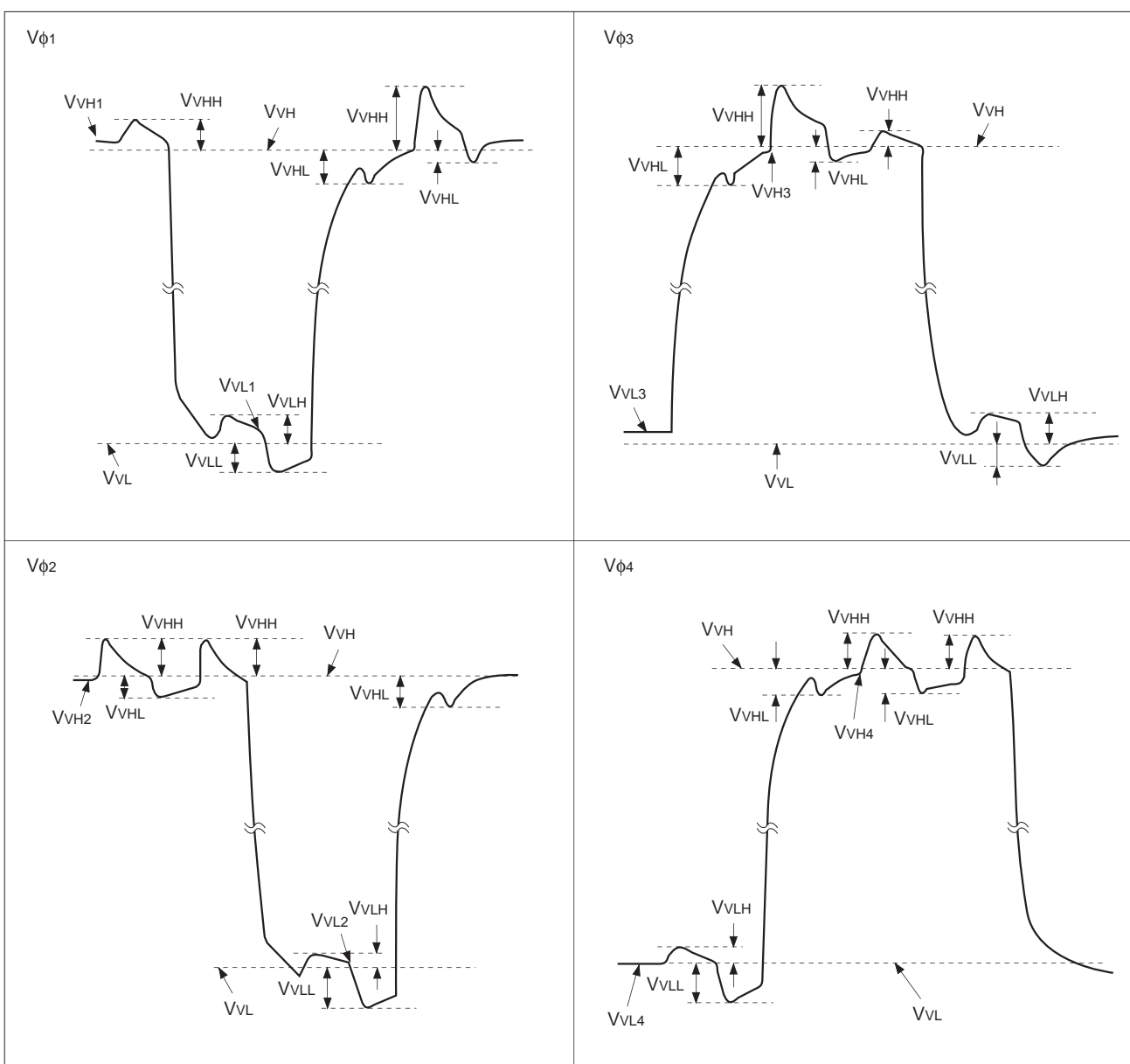
Horizontal transfer clock equivalent circuit

Drive Clock Waveform Conditions

(1) Readout clock waveform



(2) Vertical transfer clock waveform

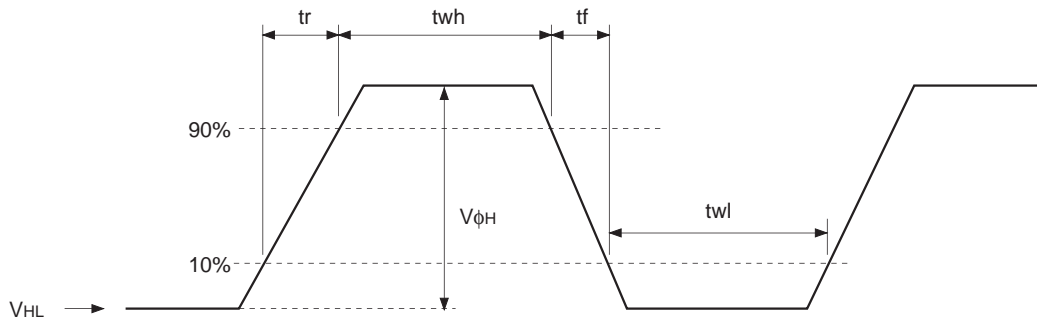


$$V_{VH} = (V_{VH1} + V_{VH2})/2$$

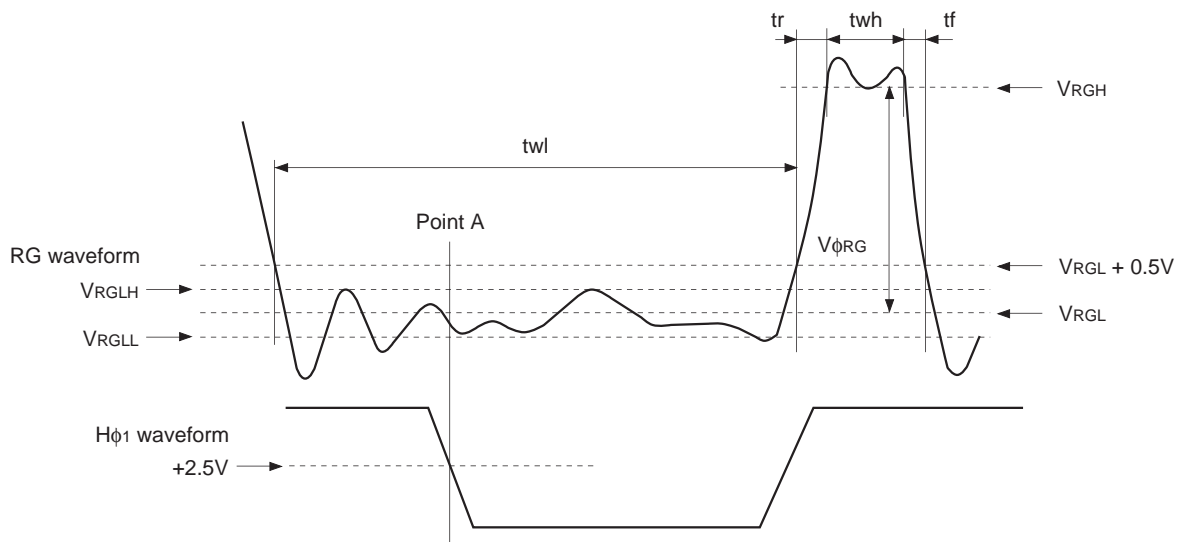
$$V_{VL} = (V_{VL3} + V_{VL4})/2$$

$$V_{\phi V} = V_{VnH} - V_{VnL} \quad (n = 1 \text{ to } 4)$$

(3) Horizontal transfer clock waveform



(4) Reset gate clock waveform



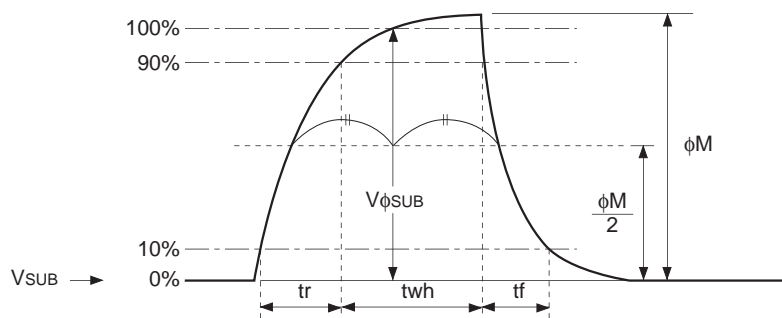
V_{RGLH} is the maximum value and V_{RGLL} is the minimum value of the coupling waveform during the period from Point A in the above diagram until the rising edge of RG. In addition, V_{RGL} is the average value of V_{RGLH} and V_{RGLL} .

$$V_{RGL} = (V_{RGLH} + V_{RGLL})/2$$

Assuming V_{RGH} is the minimum value during the interval t_{wh} , then:

$$V_{\phi RG} = V_{RGH} - V_{RGL}$$

(5) Substrate clock waveform



Clock Switching Characteristics

| Item | Symbol | twh | | | twl | | | tr | | | tf | | | Unit | Remarks |
|---------------------------|--|--------------|------|------|------|------|------|------|------|------|------|------|------|---------|---------------------|
| | | Min. | Typ. | Max. | Min. | Typ. | Max. | Min. | Typ. | Max. | Min. | Typ. | Max. | | |
| Readout clock | V_T | 2.3 | 2.5 | | | | | 0.5 | | | 0.5 | | | μs | During readout |
| Vertical transfer clock | $V_{\phi 1}, V_{\phi 2}, V_{\phi 3}, V_{\phi 4}$ | | | | | | | | | | 15 | | 250 | ns | *1 |
| Horizontal transfer clock | During imaging | | 20 | | | 20 | | | 15 | 19 | | 15 | 19 | ns | *2 |
| | During parallel-serial conversion | $H_{\phi 1}$ | | 5.38 | | | | | 0.01 | | | 0.01 | | μs | |
| | | $H_{\phi 2}$ | | | | 5.38 | | | 0.01 | | | 0.01 | | | |
| Reset gate clock | ϕ_{RG} | 11 | 13 | | | 51 | | | 3 | | | 3 | | ns | |
| Substrate clock | ϕ_{SUB} | 1.5 | 1.8 | | | | | | | 0.5 | | | 0.5 | μs | During drain charge |

*1 When vertical transfer clock driver CXD1267AN is used.

*2 $t_f \geq t_r - 2ns$.

| Item | Symbol | two | | | Unit | Remarks |
|---------------------------|--------------------------|------|------|------|------|---------|
| | | Min. | Typ. | Max. | | |
| Horizontal transfer clock | $H_{\phi 1}, H_{\phi 2}$ | 16 | 20 | | ns | *3 |

*3 The overlap period for twh and twl of horizontal transfer clocks $H_{\phi 1}$ and $H_{\phi 2}$ is two.

Image Sensor Characteristics

(Ta = 25°C)

| Item | Symbol | Min. | Typ. | Max. | Unit | Measurement method | Remarks |
|----------------------|--------------|------|---------|---------|------|--------------------|---------------|
| Sensitivity | S | 4500 | 5500 | | mV | 1 | *1 |
| Saturation signal | Vsat | 1000 | | | mV | 2 | Ta = 60°C |
| Smear | Sm | | 0.00005 | 0.00018 | % | 3 | |
| Video signal shading | SH | | | 20 | % | 4 | Zone 0 and I |
| | | | | 25 | % | 4 | Zone 0 to II' |
| Dark signal | Vdt | | | 2 | mV | 5 | Ta = 60°C |
| Dark signal shading | ΔVdt | | | 1 | mV | 6 | Ta = 60°C |
| Flicker | F | | | 2 | % | 7 | |
| Lag | Lag | | | 0.5 | % | 8 | |

*1 Sensitivity data is the conversion value by Measurement method 1.

Zone Definition of Video Signal Shading

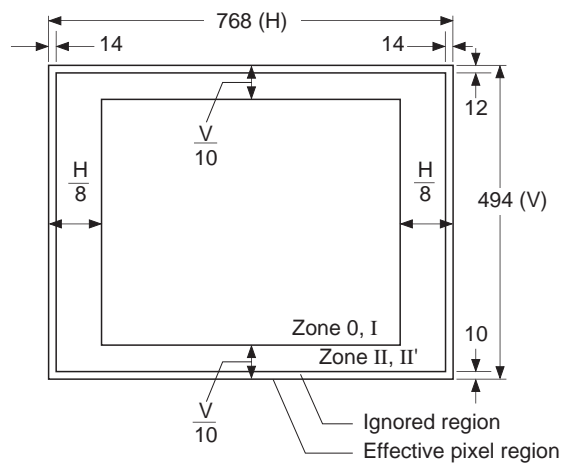


Image Sensor Characteristics Measurement Method

◎ Measurement conditions

- 1) In the following measurements, the device drive conditions are at the typical values of the bias and clock voltage conditions. (When used with substrate bias external adjustment, set the substrate voltage to the value indicated on the device and connect V_{DSUB} pin to GND or leave it open.)
- 2) In the following measurements, spot blemishes are excluded and, unless otherwise specified, the optical black (OB) level is used as the reference for the signal output, and the value measured at point [*A] in the drive circuit example is used.

◎ Definition of standard imaging conditions

- 1) Standard imaging condition I:
Use a pattern box (luminance: 706cd/m², color temperature of 3200K halogen source) as a subject. (Pattern for evaluation is not applicable.) Use a testing standard lens and image at F8. The luminous intensity to the sensor receiving surface at this point is defined as the standard sensitivity testing luminous intensity. (IR cut filter is not applicable.)
- 2) Standard imaging condition II:
Image a light source (color temperature of 3200K) with a uniformity of brightness within 2% at all angles. Use a testing standard lens and the luminous intensity is adjusted to the value indicated in each testing item by the lens diaphragm. (IR cut filter is not applicable.)

1. Sensitivity

Set to standard imaging condition I. After selecting the electronic shutter mode with a shutter speed of 1/500s, measure the signal output (V_s) at the center of the screen and substitute the value into the following formula.

$$S = V_s \times \frac{500}{60} \text{ [mV]}$$

2. Saturation signal

Set to standard imaging condition II. After adjusting the luminous intensity to 10 times the intensity with the average value of the signal output, 200mV, measure the minimum value of the signal output.

3. Smear

Set to standard imaging condition II. Adjust the luminous intensity to 500 times the intensity with the average value of the signal output, 200mV. When the readout clock is stopped and the charge drain is executed by the electronic shutter at the respective H blankings, measure the maximum value (V_{Sm} [mV]) of the signal output and substitute the value into the following formula.

$$S_m = \frac{V_{Sm}}{200} \times \frac{1}{500} \times \frac{1}{10} \times 100 \text{ [%]} \text{ (1/10V method conversion value)}$$

4. Video signal shading

Set to standard imaging condition II. Adjust the luminous intensity so that the average value of the signal output is 200mV. Then measure the maximum (V_{max} [mV]) and minimum (V_{min} [mV]) values of the signal output and substitute the values into the following formula.

$$SH = (V_{max} - V_{min})/200 \times 100 \text{ [%]}$$

5. Dark signal

Measure the average value of the signal output (Vdt [mV]) with the device ambient temperature 60°C and the device in the light-obstructed state, using the horizontal idle transfer level as a reference.

6. Dark signal shading

After measuring 5, measure the maximum (Vdmax [mV]) and minimum (Vdmin [mV]) values of the dark signal output and substitute the values into the following formula.

$$\Delta V_{dt} = V_{dmax} - V_{dmin} \text{ [mV]}$$

7. Flicker

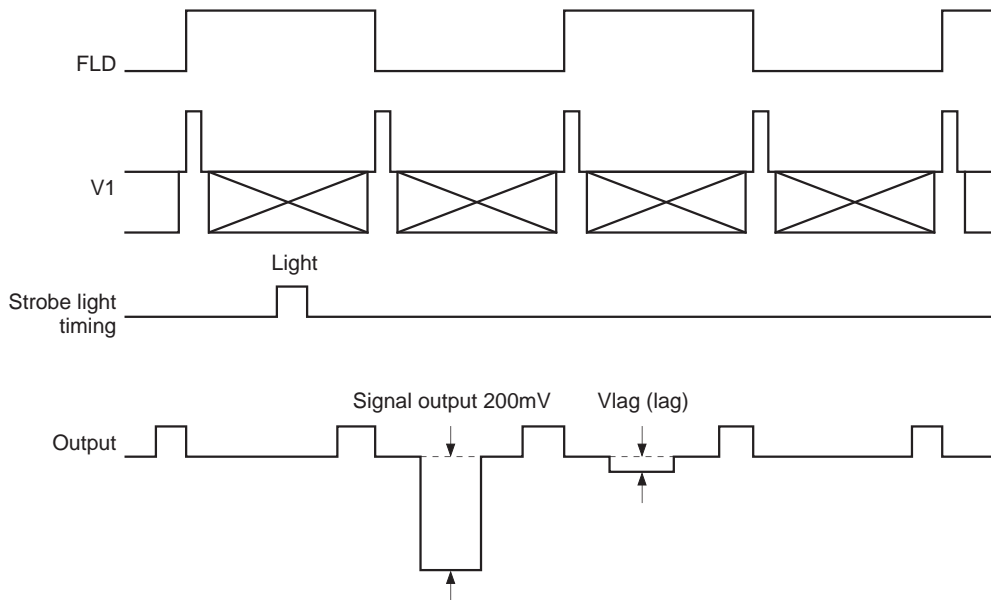
Set to standard imaging condition II. Adjust the luminous intensity so that the average value of the signal output is 200mV, and then measure the difference in the signal level between fields (ΔV_f [mV]). Then substitute the value into the following formula.

$$F = (\Delta V_f / 200) \times 100 \text{ [%]}$$

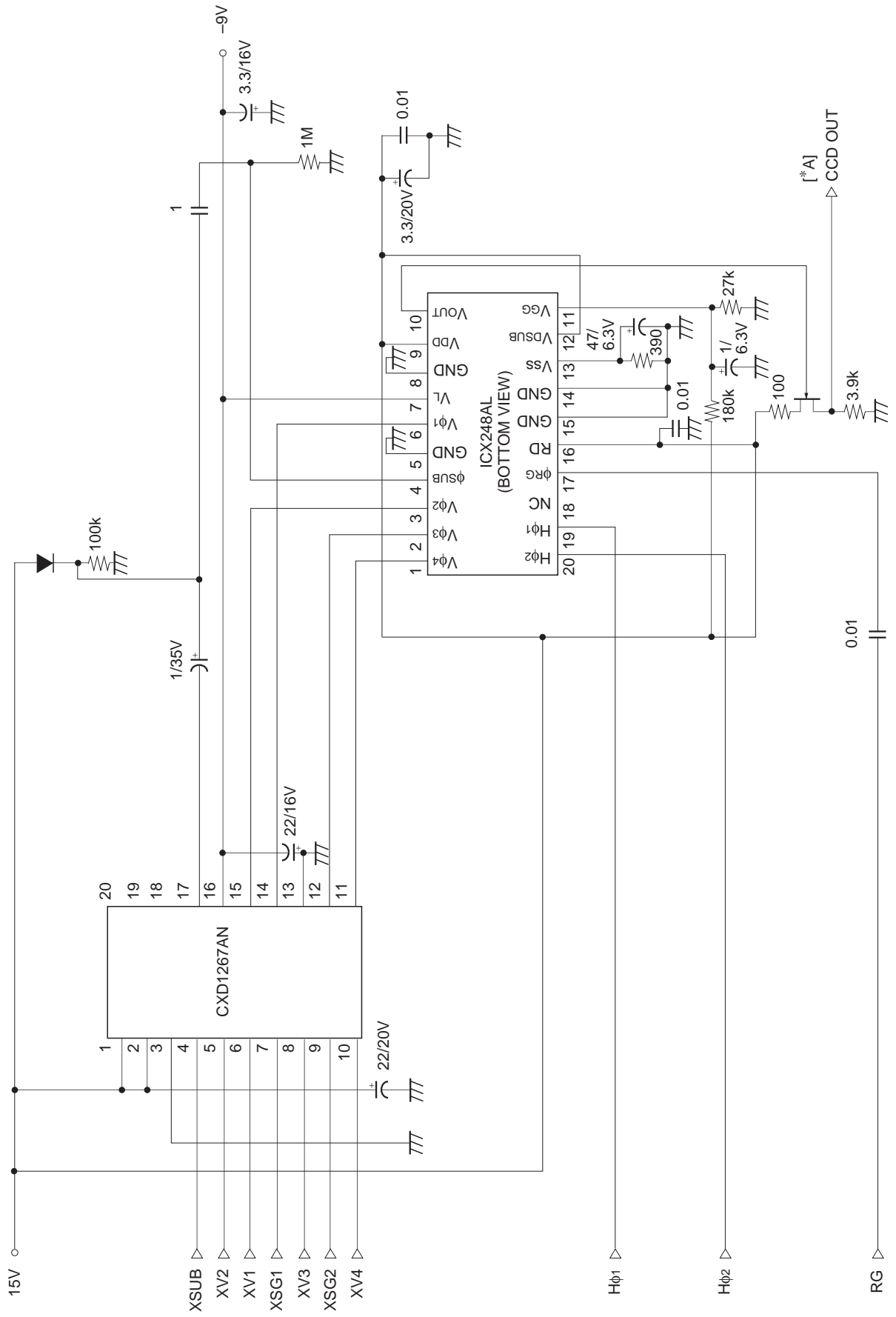
8. Lag

Adjust the signal output value generated by strobe light to 200mV. After setting the strobe light so that it strobes with the following timing, measure the residual signal (Vlag). Substitute the value into the following formula.

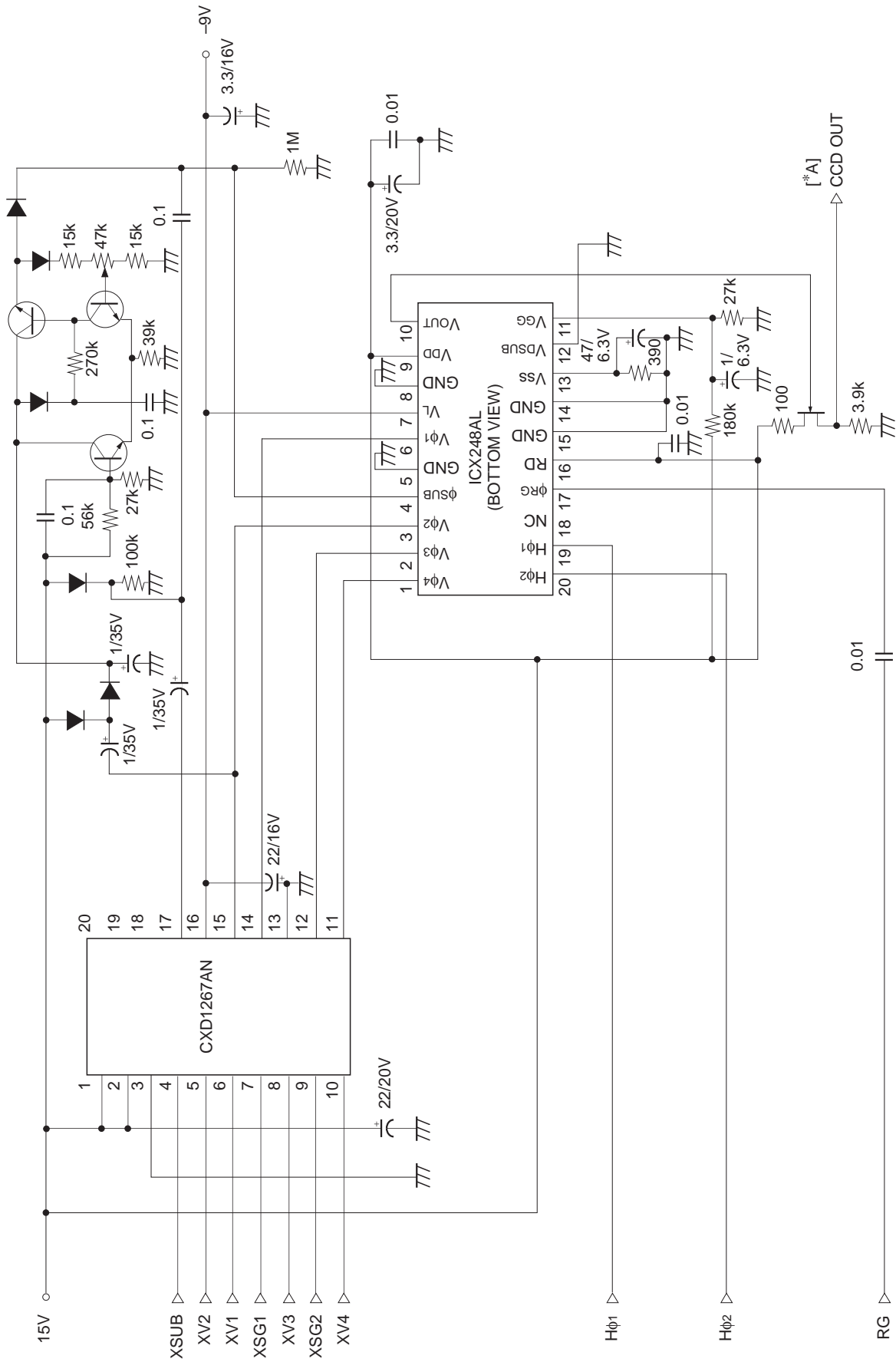
$$\text{Lag} = (V_{lag} / 200) \times 100 \text{ [%]}$$



Drive Circuit 1 (substrate bias internal generation mode)

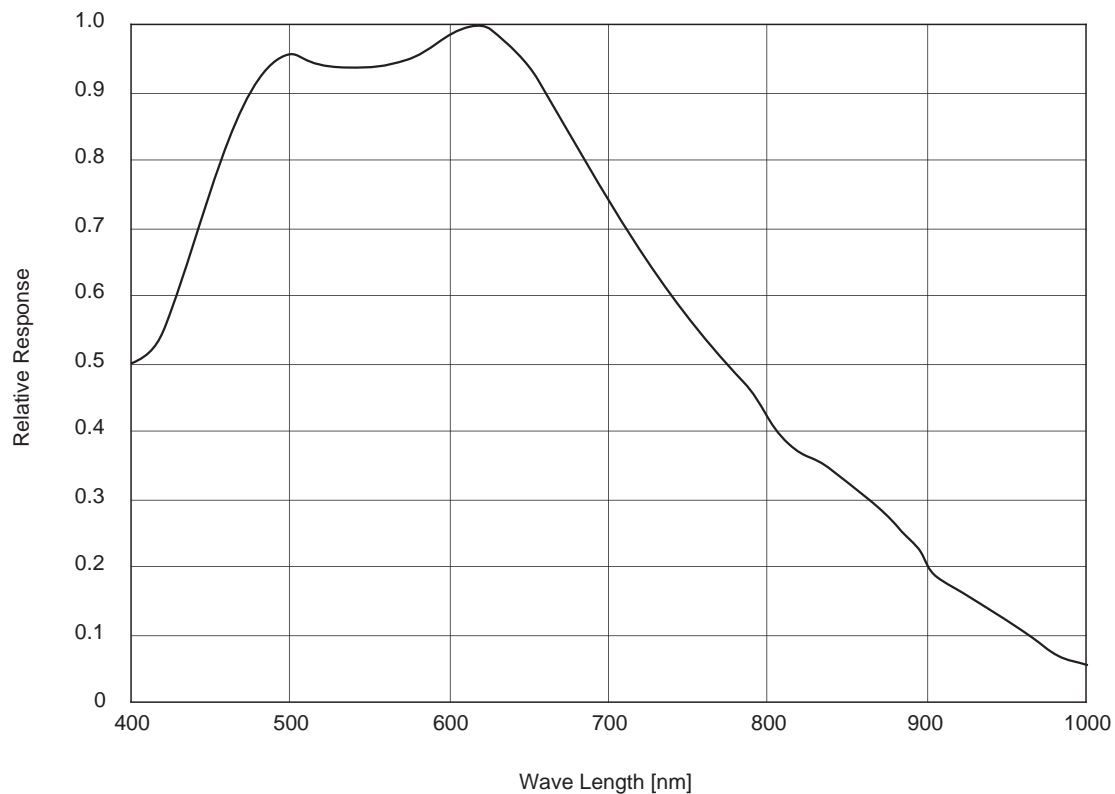


Drive Circuit 2 (substrate bias external adjustment mode)

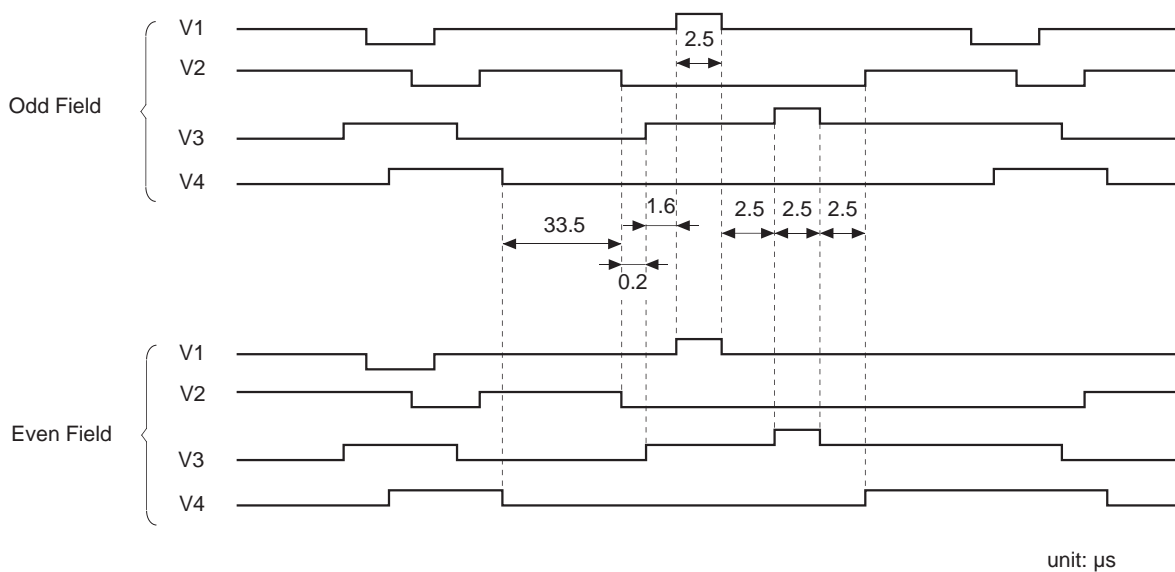


Spectral Sensitivity Characteristics

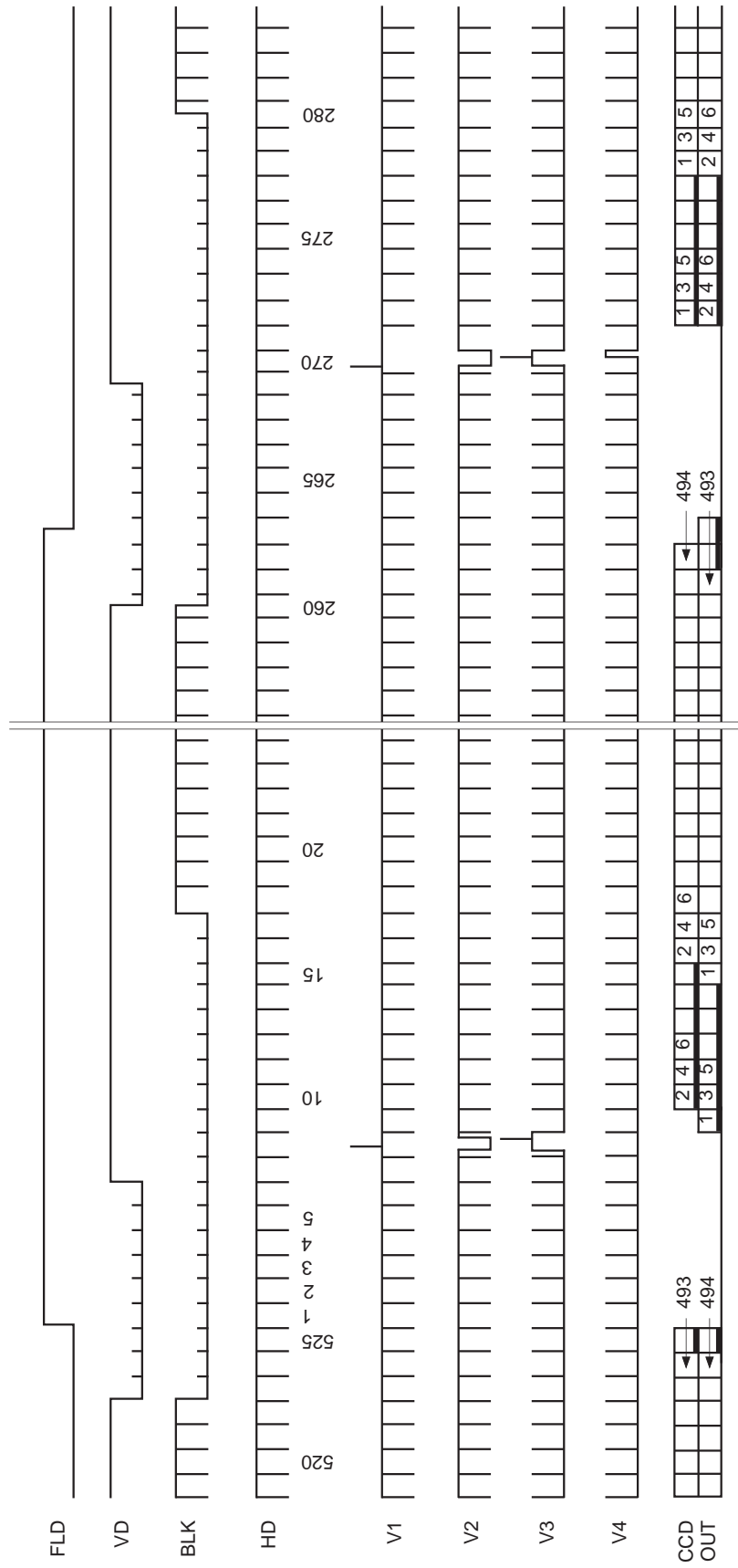
(Includes lens characteristics, excludes light source characteristics)



Sensor Readout Clock Timing Chart



Drive Timing Chart (Vertical Sync)



Notes on Handling

1) Static charge prevention

CCD image sensors are easily damaged by static discharge. Before handling be sure to take the following protective measures.

- Either handle bare handed or use non-chargeable gloves, clothes or material.
Also use conductive shoes.
- When handling directly use an earth band.
- Install a conductive mat on the floor or working table to prevent the generation of static electricity.
- Ionized air is recommended for discharge when handling CCD image sensor.
- For the shipment of mounted substrates, use boxes treated for the prevention of static charges.

2) Soldering

- Make sure the package temperature does not exceed 80°C.
- Solder dipping in a mounting furnace causes damage to the glass and other defects. Use a ground 30W soldering iron and solder each pin in less than 2 seconds. For repairs and remount, cool sufficiently.
- To dismount an image sensor, do not use a solder suction equipment. When using an electric desoldering tool, use a thermal controller of the zero cross On/Off type and connect it to ground.

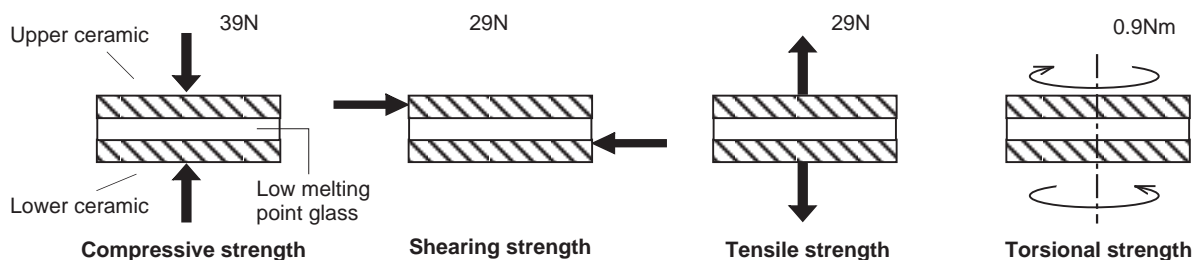
3) Dust and dirt protection

Image sensors are packed and delivered by taking care of protecting its glass plates from harmful dust and dirt. Clean glass plates with the following operation as required, and use them.

- Perform all assembly operations in a clean room (class 1000 or less).
- Do not either touch glass plates by hand or have any object come in contact with glass surfaces. Should dirt stick to a glass surface, blow it off with an air blower. (For dirt stuck through static electricity ionized air is recommended.)
- Clean with a cotton bud and ethyl alcohol if the grease stained. Be careful not to scratch the glass.
- Keep in a case to protect from dust and dirt. To prevent dew condensation, preheat or precool when moving to a room with great temperature differences.
- When a protective tape is applied before shipping, just before use remove the tape applied for electrostatic protection. Do not reuse the tape.

4) Installing (attaching)

- Remain within the following limits when applying a static load to the package. Do not apply any load more than 0.7mm inside the outer perimeter of the glass portion, and do not apply any load or impact to limited portions. (This may cause cracks in the package.)



- If a load is applied to the entire surface by a hard component, bending stress may be generated and the package may fracture, etc., depending on the flatness of the ceramic portions. Therefore, for installation, use either an elastic load, such as a spring plate, or an adhesive.

- c) The adhesive may cause the marking on the rear surface to disappear, especially in case the regulated voltage value is indicated on the rear surface. Therefore, the adhesive should not be applied to this area, and indicated values should be transferred to other locations as a precaution.
- d) The upper and lower ceramic are joined by low melting point glass. Therefore, care should be taken not to perform the following actions as this may cause cracks.
- Applying repeated bending stress to the outer leads.
 - Heating the outer leads for an extended period with a soldering iron.
 - Rapidly cooling or heating the package.
 - Applying any load or impact to a limited portion of the low melting point glass using tweezers or other sharp tools.
 - Prying at the upper or lower ceramic using the low melting point glass as a fulcrum.
- Note that the same cautions also apply when removing soldered products from boards.
- e) Acrylate anaerobic adhesives are generally used to attach CCD image sensors. In addition, cyanoacrylate instantaneous adhesives are sometimes used jointly with acrylate anaerobic adhesives. (reference)

5) Others

- a) Do not expose to strong light (sun rays) for long periods. For continuous using under cruel condition exceeding the normal using condition, consult our company.
- b) Exposure to high temperature or humidity will affect the characteristics. Accordingly avoid storage or usage in such conditions.
- c) This CCD image sensor has sensitivity in the near infrared area. Its focus may not match in the same condition under visible light /near infrared light because of aberration.

